

<b>Notice of References Cited</b>	Application/Control No. 10/730,106	Applicant(s)/Patent Under Reexamination SUZUKI ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Suzuki et al., " Scanning Electron Microscope", Pub. No: US 2003/0122074 A1, publication date: July 3, 2003.
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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